

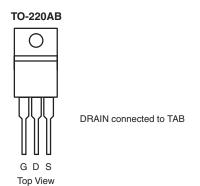
## **Power MOSFET**

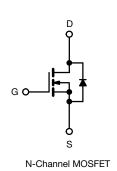
PRODUCT SUMMARY					
V <sub>DS</sub> (V)	200				
$R_{DS(on)}(\Omega)$	V <sub>GS</sub> = 10 V 0.20				
Q <sub>g</sub> max. (nC)	70				
Q <sub>gs</sub> (nC)	13				
Q <sub>gd</sub> (nC)	39				
Configuration	Single				

#### **FEATURES**

- Surface mount
- Low-profile through-hole
- Available in tape and reel
- Dynamic dV/dt rating
- 150 °C operating temperature
- Fast switching
- Fully avalanche rated







<b>ABSOLUTE MAXIMUM RATINGS</b> (T <sub>C</sub> = 25 °C, unless otherwise noted)						
PARAMETER			SYMBOL	LIMIT	UNIT	
Drain-Source Voltage			$V_{DS}$	200	V	
Gate-Source Voltage			$V_{GS}$	± 20	V	
Continuous Drain Current	V <sub>GS</sub> at 10 V	$T_{\rm C} = 25  ^{\circ}{\rm C}$ $T_{\rm C} = 100  ^{\circ}{\rm C}$	- I <sub>D</sub>	14		
		T <sub>C</sub> = 100 °C		10	Α	
Pulsed Drain Current a, e			I <sub>DM</sub>	56		
Linear Derating Factor				1.0	W/°C	
Single Pulse Avalanche Energy b, e			E <sub>AS</sub>	580	mJ	
Avalanche Current <sup>a</sup>			I <sub>AR</sub>	15	Α	
Repetitive Avalanche Energy <sup>a</sup>			E <sub>AR</sub>	13	mJ	
Maximum Power Dissipation	T <sub>C</sub> = 25 °C		$P_{D}$	110	w	
	T <sub>A</sub> = 25 °C			3.1	VV	
Peak Diode Recovery dV/dt c, e			dV/dt	5.0	V/ns	
Operating Junction and Storage Temperature Range			T <sub>J</sub> , T <sub>stg</sub>	-55 to +150	- °C	
Soldering Recommendations (Peak temperature) d for 10 s				300	]	

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11). b.  $V_{DD} = 50$  V, starting  $T_J = 25$  °C, L = 2.7 mH,  $R_g = 25$   $\Omega$ ,  $I_{AS} = 18$  A (see fig. 12). c.  $I_{SD} \le 18$  A,  $I_{AS} = 18$  A,  $I_{AS} = 18$  A (see fig. 12).

- d. 1.6 mm from case.
- e. Uses IRF640, SiHF640 data and test conditions.



THERMAL RESISTANCE RATINGS					
PARAMETER	SYMBOL	TYP.	MAX.	UNIT	
Maximum Junction-to-Ambient (PCB mounted, steady-state) <sup>a</sup>	R <sub>thJA</sub>	-	40	°C/W	
Maximum Junction-to-Case (Drain)	R <sub>thJC</sub>	-	1.0		

#### Note

a. When mounted on 1" square PCB (FR-4 or G-10 material).

PARAMETER	SYMBOL	TEST CONDITIONS		MIN.	TYP.	MAX.	UNIT
Static					L		
Drain-Source Breakdown Voltage	V <sub>DS</sub>	V <sub>GS</sub> :	= 0 V, I <sub>D</sub> = 250 μA	200	-	-	V
V <sub>DS</sub> Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Reference	e to 25 °C, I <sub>D</sub> = 1 mA °	-	0.29	-	V/°C
Gate-Source Threshold Voltage	V <sub>GS(th)</sub>	V <sub>DS</sub> =	= V <sub>GS</sub> , I <sub>D</sub> = 250 μA	1.0	-	3.0	V
Gate-Source Leakage	I <sub>GSS</sub>		V <sub>GS</sub> = ± 20 V	-	-	± 100	nA
Zovo Coto Voltago Dvois Current		V <sub>DS</sub> =	= 200 V, V <sub>GS</sub> = 0 V	-	-	25	μА
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>DS</sub> = 160 \	/, V <sub>GS</sub> = 0 V, T <sub>J</sub> = 125 °C	-	-	250	
Drain-Source On-State Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = 10 V	I <sub>D</sub> = 11 A <sup>b</sup>	-	0.20	0.25	Ω
Forward Transconductance	9 <sub>fs</sub>	V <sub>DS</sub> =	= 50 V, I <sub>D</sub> = 11 A <sup>d</sup>	6.7	-	-	S
Dynamic							
Input Capacitance	C <sub>iss</sub>		$V_{GS} = 0 V$ ,		1300	-	
Output Capacitance	C <sub>oss</sub>		$V_{DS} = 25 \text{ V},$	-	430	-	рF
Reverse Transfer Capacitance	C <sub>rss</sub>	f = 1.0 MHz, see fig. 5 <sup>d</sup>		-	130	-	1
Total Gate Charge	Qg			-	-	70	
Gate-Source Charge	Q <sub>gs</sub>	$V_{GS} = 10 \text{ V}$	$V_{GS} = 10 \text{ V}$ $I_D = 18 \text{ A}, V_{DS} = 160 \text{ V},$ see fig. 6 and 13 b, c		-	13	nC
Gate-Drain Charge	Q <sub>gd</sub>	see lig. 6 and 13 2, 5		-	-	39	
Turn-On Delay Time	t <sub>d(on)</sub>			-	14	-	
Rise Time	t <sub>r</sub>	V <sub>DD</sub> = 100 V, I <sub>D</sub> = 18 A,		-	51	-	ns
Turn-Off Delay Time	t <sub>d(off)</sub>	$R_g = 9.1 \Omega$ , F	$R_g = 9.1  \Omega$ , $R_D = 5.4  \Omega$ , see fig. 10 b, c		45	-	
Fall Time	t <sub>f</sub>				36	-	
Gate Input Resistance	$R_g$	f = 1	MHz, open drain	0.5	-	3.6	Ω
Drain-Source Body Diode Characteristic	s						
Continuous Source-Drain Diode Current	I <sub>S</sub>	MOSFET sym showing the	MOSFET symbol showing the		-	18	۸
Pulsed Diode Forward Current <sup>a</sup>	I <sub>SM</sub>	integral reverse p - n junction diode		-	-	72	Α
Body Diode Voltage	V <sub>SD</sub>	T <sub>J</sub> = 25 °C, I <sub>S</sub> = 18 A, V <sub>GS</sub> = 0 V b		-	-	2.0	V
Body Diode Reverse Recovery Time	t <sub>rr</sub>	$T_J = 25 ^{\circ}\text{C}$ , $I_F = 18 \text{A}$ , $dI/dt = 100 \text{A/}\mu\text{s}^{\text{b, c}}$		-	300	610	ns
Body Diode Reverse Recovery Charge	$Q_{rr}$			-	3.4	7.1	μC
Forward Turn-On Time	t <sub>on</sub>	Intrinsic turn-on time is negligible (turn-on is dominated by L <sub>S</sub> and L <sub>D</sub> )				L <sub>D</sub> )	

#### Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- b. Pulse width  $\leq 300~\mu s;$  duty cycle  $\leq 2~\%.$
- c. Uses IRF640/SiHF640 data and test conditions.



### TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

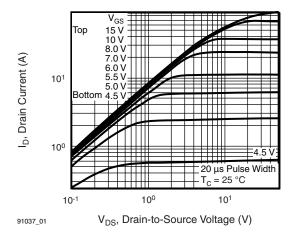


Fig. 1 - Typical Output Characteristics, T<sub>J</sub> = 25 °C

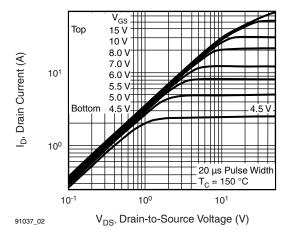


Fig. 2 - Typical Output Characteristics,  $T_J$  = 175 °C

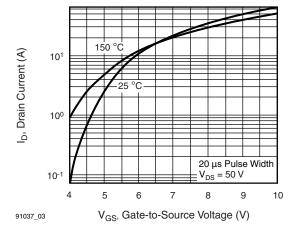


Fig. 3 - Typical Transfer Characteristics

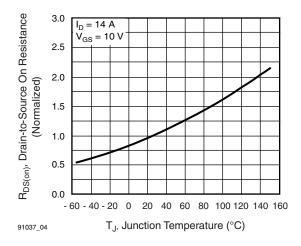


Fig. 4 - Normalized On-Resistance vs. Temperature

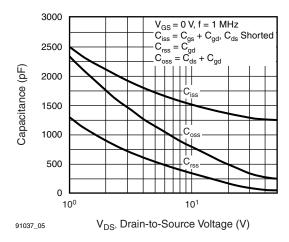


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

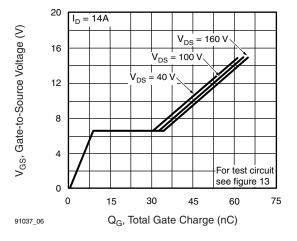


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage



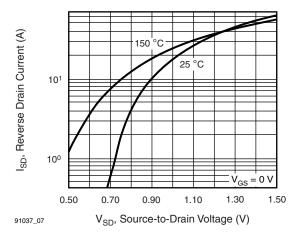


Fig. 7 - Typical Source-Drain Diode Forward Voltage

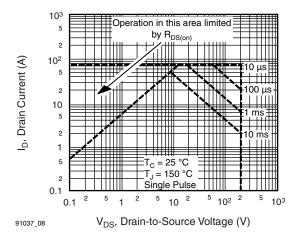


Fig. 8 - Maximum Safe Operating Area

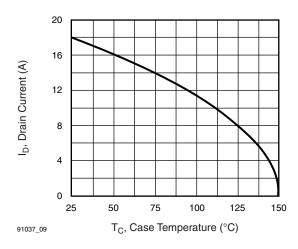


Fig. 9 - Maximum Drain Current vs. Case Temperature

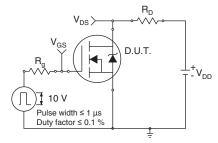


Fig. 10a - Switching Time Test Circuit

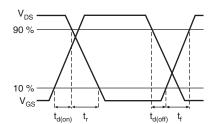


Fig. 10b - Switching Time Waveforms

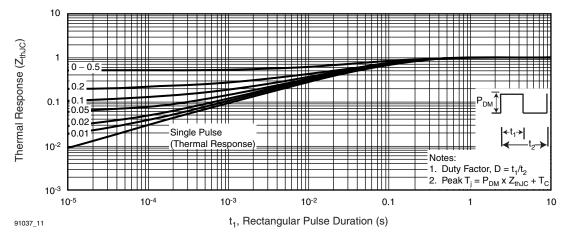


Fig. 10 - Maximum Effective Transient Thermal Impedance, Junction-to-Case



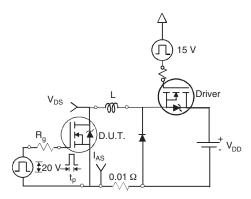


Fig. 12a - Unclamped Inductive Test Circuit

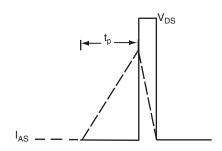


Fig. 12b - Unclamped Inductive Waveforms

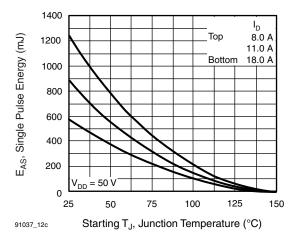


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

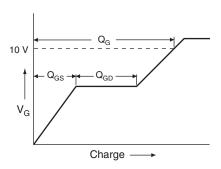


Fig. 13a - Basic Gate Charge Waveform

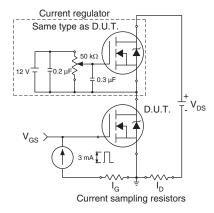
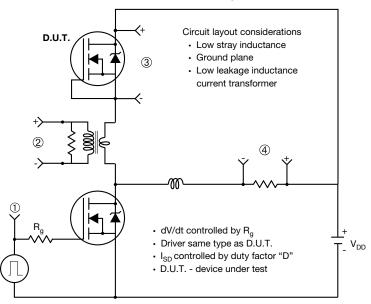


Fig. 13b - Gate Charge Test Circuit



#### Peak Diode Recovery dV/dt Test Circuit



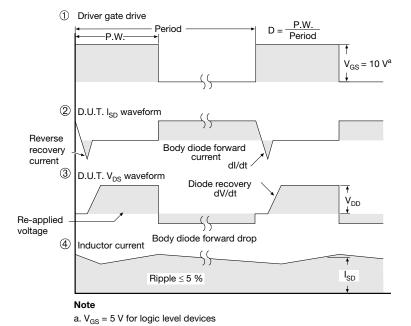
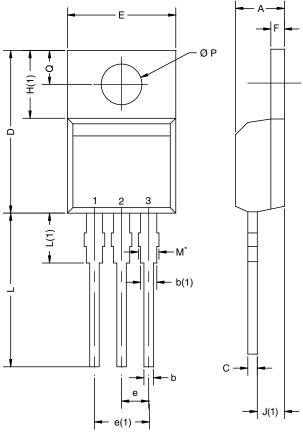


Fig. 14 - For N-Channel



# **TO-220AB**



- e(	e 1) b	C-
		D2

	MILLIM	IETERS	INCHES		
DIM.	MIN.	MAX.	MIN.	MAX.	
Α	4.25	4.65	0.167	0.183	
b	0.69	1.01	0.027	0.040	
b(1)	1.20	1.73	0.047	0.068	
С	0.36	0.61	0.014	0.024	
D	14.85	15.49	0.585	0.610	
D2	12.19	12.70	0.480	0.500	
Е	10.04	10.51	0.395	0.414	
е	2.41	2.67	0.095	0.105	
e(1)	4.88	5.28	0.192	0.208	
F	1.14	1.40	0.045	0.055	
H(1)	6.09	6.48	0.240	0.255	
J(1)	2.41	2.92	0.095	0.115	
L	13.35	14.02	0.526	0.552	
L(1)	3.32	3.82	0.131	0.150	
ØР	3.54	3.94	0.139	0.155	
Q	2.60	3.00	0.102	0.118	
ECN: T14-0413-Rev. P, 16-Jun-14 DWG: 5471					

#### Note

 $<sup>^{\</sup>star}$  M = 1.32 mm to 1.62 mm (dimension including protrusion) Heatsink hole for HVM



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